



FOR IMMEDIATE RELEASE

**Contacts:**

**Aehr Test Systems**

Ken Spink  
Chief Financial Officer  
(510) 623-9400 x309

**MKR Group Inc.**

Todd Kehrli or Jim Byers  
Analyst/Investor Contact  
(323) 468-2300  
aehr@mkr-group.com

**Aehr Test Systems to Announce Second Quarter Fiscal 2016 Financial Results  
on January 12, 2016**

**Fremont, CA (December 28, 2015)** – Aehr Test Systems (NASDAQ: AEHR), a worldwide supplier of semiconductor test and burn-in equipment, today announced that it will report financial results for its second quarter of fiscal 2016 ended November 30, 2015 on Tuesday, January 12, 2016 following the close of the market. The Company will host a conference call and webcast at 5:00 p.m. Eastern time to discuss the results.

**What:** Aehr Test Systems second quarter fiscal 2016 financial results conference call

**When:** Tuesday, January 12<sup>th</sup> at 5:00 p.m. Eastern Time (2:00 p.m. PT)

**Dial in Number:** To access the live call, dial **888-437-9445** (US and Canada) or **719-325-2495** (International) and give the participant passcode **6806024**.

**Webcast:** To access the live webcast, please visit the investor relations section at [www.aehr.com](http://www.aehr.com).

**Call Replay:** A phone replay of the call will be available approximately two hours following the end of the call through 8:00 p.m. ET on Tuesday, January 19, 2016.

**Replay Numbers:** **888-203-1112** (US and Canada)  
**719-457-0820** (International)  
Replay passcode: **6806024**

**About Aehr Test Systems**

Headquartered in Fremont, California, Aehr Test Systems is a worldwide provider of test systems for burning-in and testing logic and memory integrated circuits and has an installed base of more than 2,500 systems worldwide. Increased quality and reliability needs of the Automotive and Mobility integrated circuit markets are driving additional test requirements, capacity needs and opportunities for Aehr Test products in package and wafer level test. Aehr Test has developed and introduced several innovative products, including the ABTS™ and FOX™ families of test and burn-in systems and the DiePak® carrier. The ABTS system is used in production and qualification testing of packaged parts for both lower-power and higher-power logic as well as all common types of memory devices. The FOX system is a full wafer contact test and burn-in system used for burn-in and functional test of complex devices, such as leading-edge memories, digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company's website at [www.aehr.com](http://www.aehr.com).

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